

Lasing Reporting Summary

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▶ Experimental design

Please check: are the following details reported in the manuscript?

1. Threshold

Plots of device output power versus pump power over a wide range of values indicating a clear threshold

 Yes

 No

2. Linewidth narrowing

Plots of spectral power density for the emission at pump powers below, around, and above the lasing threshold, indicating a clear linewidth narrowing at threshold

 Yes

 No

Resolution of the spectrometer used to make spectral measurements

 Yes

 No

3. Coherent emission

Measurements of the coherence and/or polarization of the emission

 Yes

 No

4. Beam spatial profile

Image and/or measurement of the spatial shape and profile of the emission, showing a well-defined beam above threshold

 Yes

 No

5. Operating conditions

Description of the laser and pumping conditions
Continuous-wave, pulsed, temperature of operation

 Yes

 No

Threshold values provided as density values (e.g. W cm⁻² or J cm⁻²) taking into account the area of the device

 Yes

 No

6. Alternative explanations

Reasoning as to why alternative explanations have been ruled out as responsible for the emission characteristics
e.g. amplified spontaneous, directional scattering; modification of fluorescence spectrum by the cavity

 Yes

 No

7. Theoretical analysis

Theoretical analysis that ensures that the experimental values measured are realistic and reasonable
e.g. laser threshold, linewidth, cavity gain-loss, efficiency

 Yes

 No

8. Statistics

Number of devices fabricated and tested

 Yes

 No

Statistical analysis of the device performance and lifetime (time to failure)

 Yes

 No

